

DEEP LEARNING FOR MANUFACTURING

Predicting and Preventing Manufacturing Defects

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Challenges faced in application of Artificial Intelligence within manufacturing systems

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COMPETITIVE ADVANTAGE

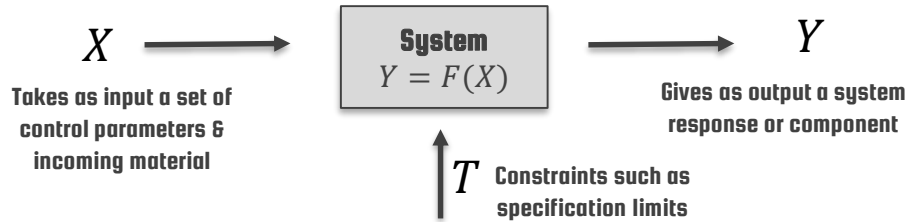
Potential benefits that can be expected on application of CAE and AI software within the closed-loop framework

FRAMEWORK

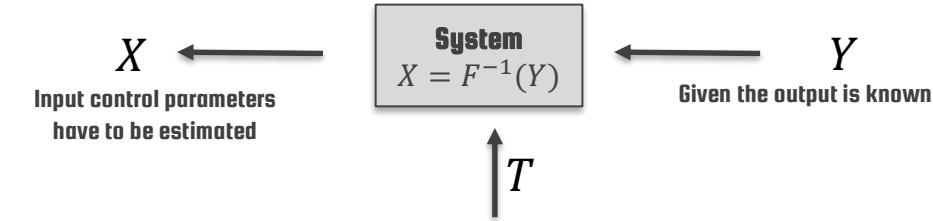


Intelligent & Automated Root Cause Analysis (RCA) for multi-stage production/assembly systems

Analysis of a system: Forward Propagation *CAE Simulation*



Synthesis of a system: Backward Propagation *Artificial Intelligence: Deep Learning*



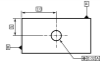
Estimating F
enables:



Process Parameter
Optimization



Fixture
Optimization



Tolerance
Analysis

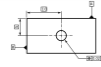
Estimating F^{-1}
enables:



Root Cause
Analysis



Process Control and
Correction



Tolerance
Synthesis

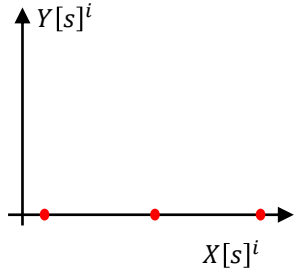


FRAMEWORK

How is Root Cause Analysis done using Computer Aided Engineering (CAE) and Deep Learning?

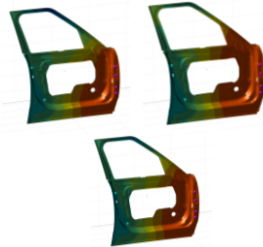
Step 1: Intelligent Sampling of X

$X[s]^i = \text{Sampling}(X)$



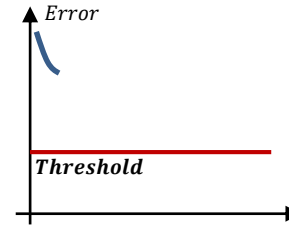
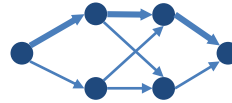
Step 2: Response Evaluation Y using CAE simulation

$Y[s]^i = \hat{F}(X[s]^i)$



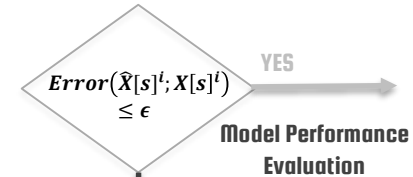
Step 3: Deep Learning Model Building

$\hat{X}[s]^i = \hat{F}_i^{-1}(Y[s]^i)$



Step 4: Trained Model Deployment

$\hat{X} = \hat{F}^{-1}(Y[s]^i)$



$\hat{X}[s]^i, \sigma(\hat{Y}[s]^i)$ for $i = 1, 2, 3 \dots, N$

\hat{F}, \hat{X} are estimates for F and X while i represents the iteration that goes from $i = 1, 2, 3$ to N until the model error is below the required threshold ϵ
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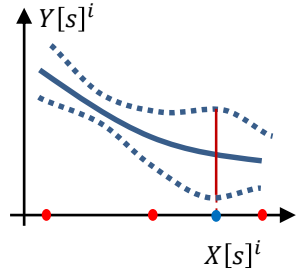


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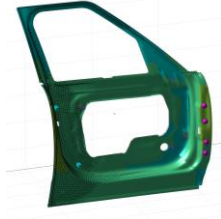
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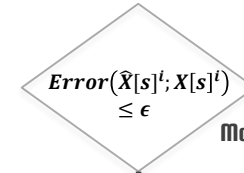
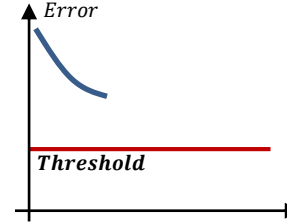
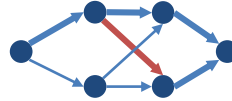
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Model Performance Evaluation

NO

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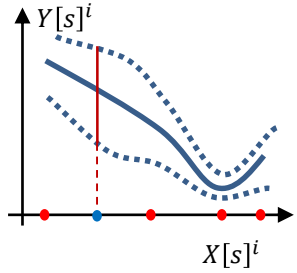


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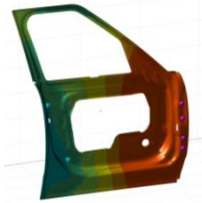
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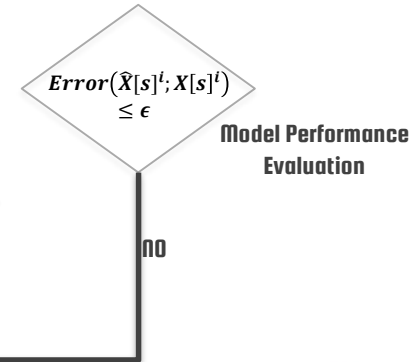
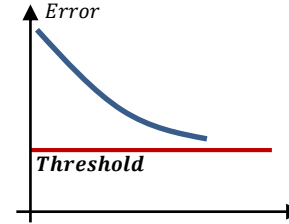
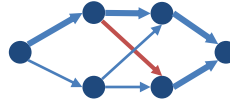
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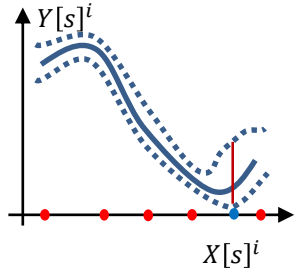


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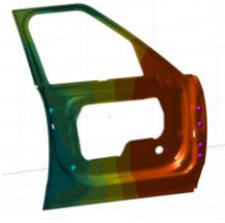
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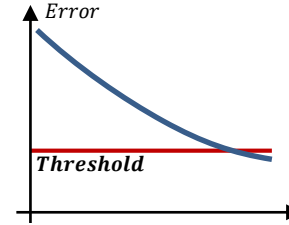
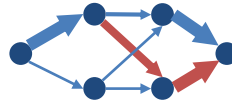
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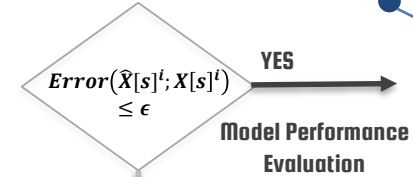
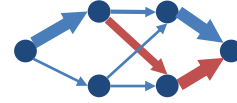
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Step 4: Trained Model Deployment

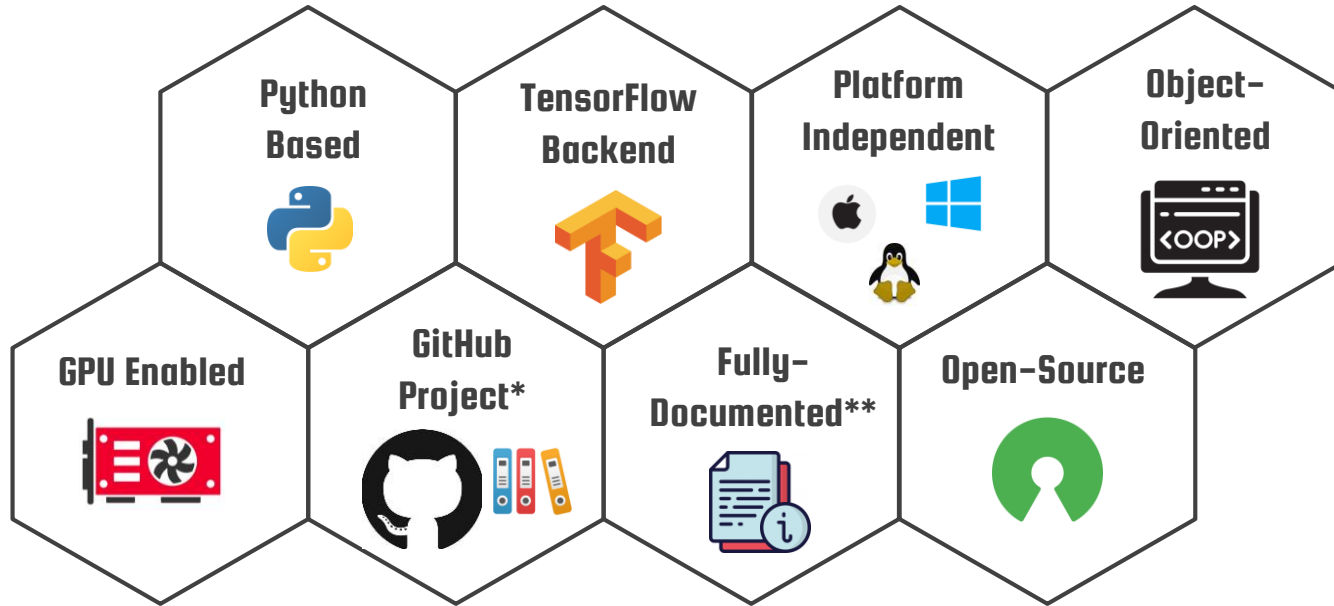
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SOFTWARE - Overview



In the pipeline:



Distributed Computing



Advance Multi-Stage Case Studies

GitHub Project*: https://github.com/sumitsinha/Deep_Learning_for_Manufacturing

Documentation**: https://sumitsinha.github.io/Deep_Learning_for_Manufacturing/html/index.html

SOFTWARE - NOVELTY



Uncertainty Quantification



System Dimensionality



Architecture Selection



System Collinearity

Probabilistic Model using Bayesian Inference

Used to quantify the uncertainty of predictions using approximate Bayesian inference

Active Learning

Adaptive sampling strategies to handle the dimensionality of the system

3D CNN Architecture*

Optimized 3D Convolutional neural network model architectures

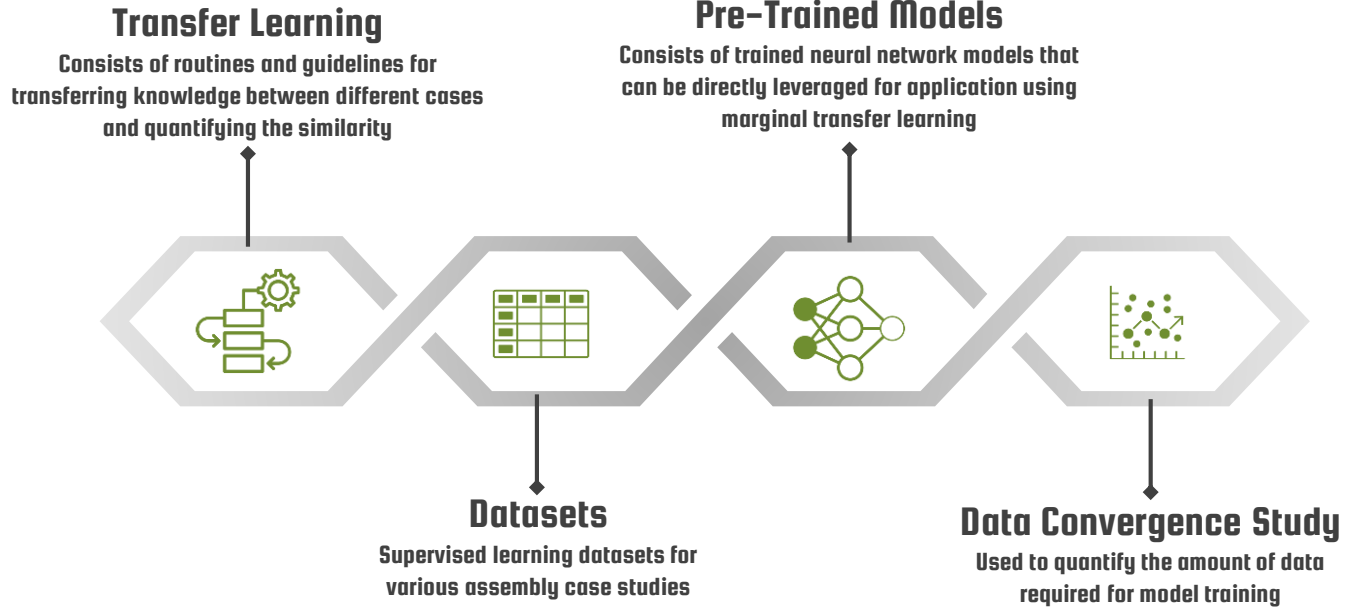
Gaussian Mixture based Multi-Mode Output Model

Used to handle the collinearities present within a system

The library includes implementation of novel research and development to solve the stated challenges

**Sinha, S., Glorieux, E., Franciosa, P., & Ceglarek, D. (2019, June). 3D convolutional neural networks to estimate assembly process parameters using 3D point-clouds. In Multimodal Sensing: Technologies and Applications (Vol. 11059, p. 110590B). International Society for Optics and Photonics.*

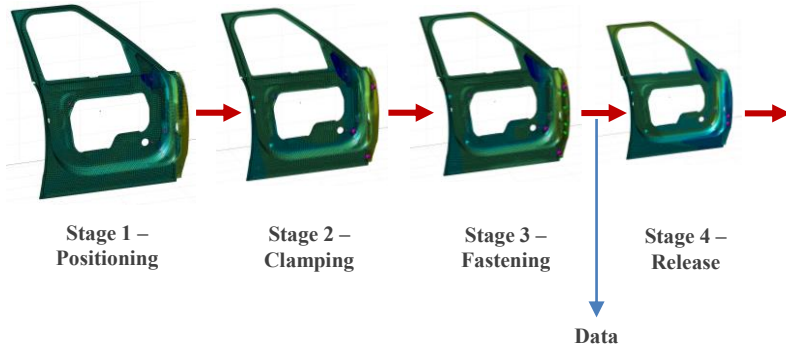
SOFTWARE - SOLUTIONS



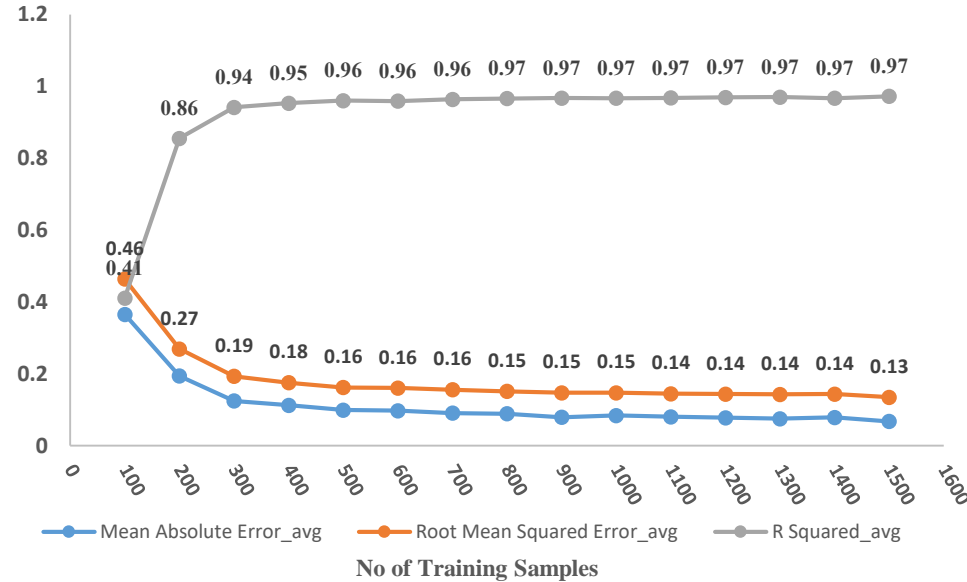
The library also includes datasets and key modules for various tasks not included in standard deep learning libraries, that help solve the **model transferability challenges**

SOFTWARE – CASE STUDY

Target: Intelligent Root Cause Analysis for two-part assembly



If data is collected at stage 3, the model converges with 1000 training samples with a root mean square error (RMSE) of 0.14 and R-squared value of 0.97

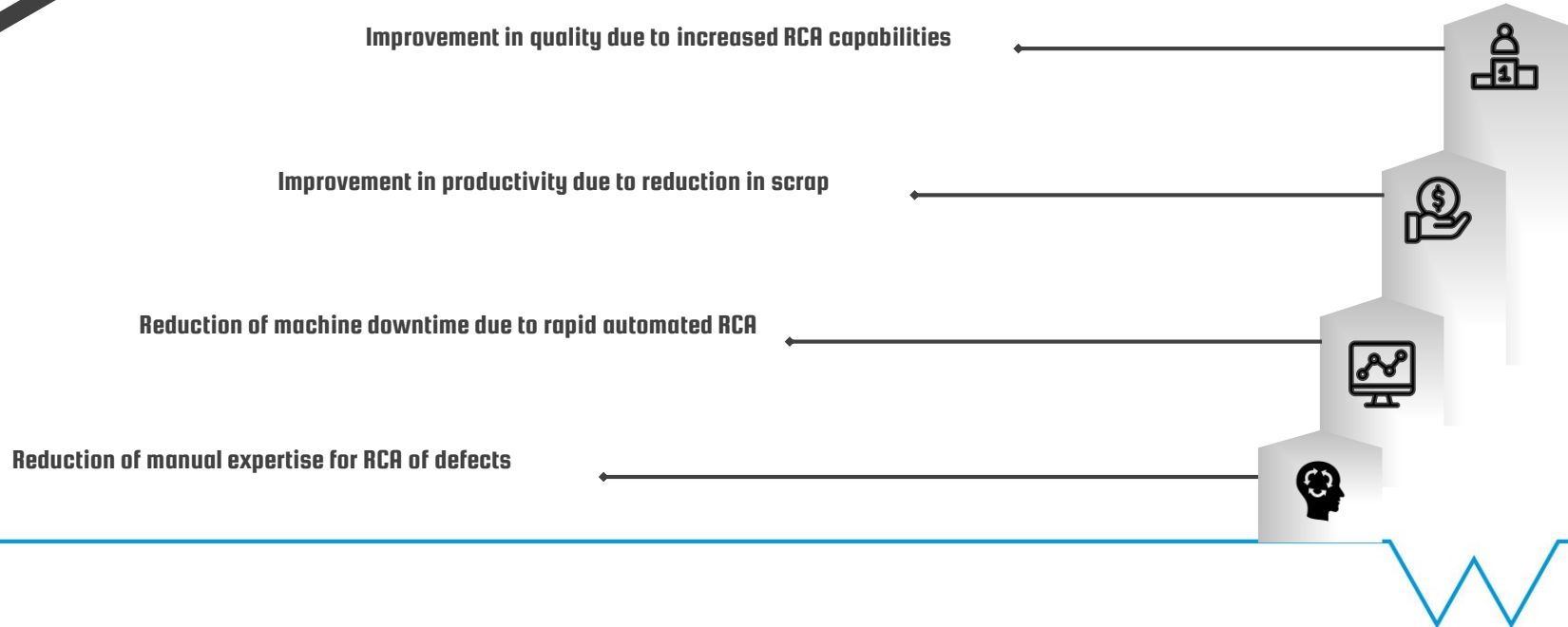


Testing is done up to double of the specification limit used for training

COMPETITIVE ADVANTAGE



Application and integration of CAE Simulation with deep learning ensures early **estimation and prediction** of process parameter variations hence they can be **prevented** from manifesting into product defects



COMPETITIVE ADVANTAGE

Current Scenario

Only Product Data

Only having product data can only be used for monitoring and not RCA



- Limited RCA capabilities/only monitoring
- Requirement of manual expertise
- No/limited data for AI model training



Process data sensors for all parameters

Directly obtain process data for each parameter without the need for any learning



High RCA Capabilities



- High costs
- Difficult to setup within an online system



Product Data + CAE Simulation + Artificial Intelligence

Use AI model trained on real and simulated data to model relationship and suggest minimum additional process sensors in various sub-stages of the system



- Low costs
- High RCA Capabilities
- Strategic sensor placement

THANK-YOU

Does anyone have any questions?

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